



ALPHA & OMEGA
SEMICONDUCTOR

AOTS26108
30V/20V Complementary MOSFET

General Description

- Trench Power MOSFET technology
- Low $R_{DS(ON)}$
- Low Gate Charge
- RoHS and Halogen-Free Compliant

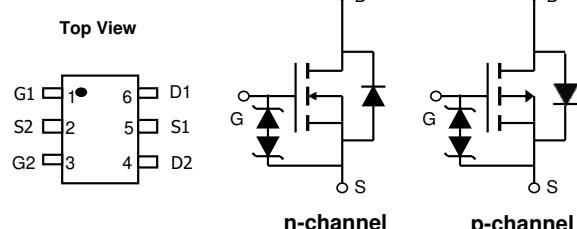
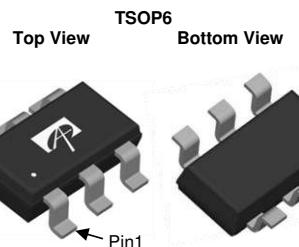
Applications

- This device is ideal for Load Switch

Product Summary

| N-Channel | P-Channel |
|-------------------------------|---------------------------|
| $V_{DS} = 30V$ | -20V |
| $I_D = 3.8A$ ($V_{GS}=10V$) | -4.5A ($V_{GS}=-4.5V$) |
| $R_{DS(ON)}$ | $R_{DS(ON)}$ |
| < 50mΩ ($V_{GS}=10V$) | < 44mΩ ($V_{GS}=-4.5V$) |
| < 57mΩ ($V_{GS}=4.5V$) | < 59mΩ ($V_{GS}=-2.5V$) |
| < 72mΩ ($V_{GS}=2.5V$) | < 80mΩ ($V_{GS}=-1.8V$) |

ESD protection



Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

| Parameter | Symbol | Max n-channel | Max p-channel | Units |
|--|------------------|---------------|---------------|-------|
| Drain-Source Voltage | V_{DS} | 30 | -20 | V |
| Gate-Source Voltage | V_{GS} | ± 12 | ± 8 | V |
| Continuous Drain Current | $T_A=25^\circ C$ | 3.8 | -4.5 | A |
| Current | | 3 | -3.6 | |
| Pulsed Drain Current ^C | I_{DM} | 15 | -18 | |
| Power Dissipation ^B | $T_A=25^\circ C$ | 1.25 | 1.25 | W |
| | | 0.80 | 0.80 | |
| Junction and Storage Temperature Range | T_J, T_{STG} | -55 to 150 | | °C |

Thermal Characteristics

| Parameter | Symbol | Typ | Max | Units |
|--|-----------------|-----|-----|-------|
| Maximum Junction-to-Ambient ^A $t \leq 10s$ | $R_{\theta JA}$ | 75 | 100 | °C/W |
| Maximum Junction-to-Ambient ^{A,D} Steady-State | | 105 | 130 | °C/W |
| Maximum Junction-to-Lead | $R_{\theta JL}$ | 50 | 65 | °C/W |

N-Channel Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

| Symbol | Parameter | Conditions | Min | Typ | Max | Units |
|-----------------------------|---------------------------------------|---|-----|-----|----------|------------------|
| STATIC PARAMETERS | | | | | | |
| BV_{DSS} | Drain-Source Breakdown Voltage | $I_D=250\mu\text{A}, V_{GS}=0\text{V}$ | 30 | | | V |
| I_{DSS} | Zero Gate Voltage Drain Current | $V_{DS}=30\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$ | | 1 | 5 | μA |
| I_{GSS} | Gate-Body leakage current | $V_{DS}=0\text{V}, V_{GS}=\pm 12\text{V}$ | | | ± 10 | μA |
| $V_{GS(\text{th})}$ | Gate Threshold Voltage | $V_{DS}=V_{GS}, I_D=250\mu\text{A}$ | 0.5 | 1 | 1.5 | V |
| $R_{DS(\text{ON})}$ | Static Drain-Source On-Resistance | $V_{GS}=10\text{V}, I_D=3.8\text{A}$ $T_J=125^\circ\text{C}$ | | 40 | 50 | $\text{m}\Omega$ |
| | | $V_{GS}=4.5\text{V}, I_D=3.6\text{A}$ | | 42 | 57 | $\text{m}\Omega$ |
| | | $V_{GS}=2.5\text{V}, I_D=3.2\text{A}$ | | 50 | 72 | $\text{m}\Omega$ |
| g_{FS} | Forward Transconductance | $V_{DS}=5\text{V}, I_D=3.8\text{A}$ | | 20 | | S |
| V_{SD} | Diode Forward Voltage | $I_S=1\text{A}, V_{GS}=0\text{V}$ | | 0.7 | 1 | V |
| I_S | Maximum Body-Diode Continuous Current | | | | 1.5 | A |
| DYNAMIC PARAMETERS | | | | | | |
| C_{iss} | Input Capacitance | $V_{GS}=0\text{V}, V_{DS}=15\text{V}, f=1\text{MHz}$ | | 340 | | pF |
| C_{oss} | Output Capacitance | | | 30 | | pF |
| C_{rss} | Reverse Transfer Capacitance | | | 25 | | pF |
| R_g | Gate resistance | $f=1\text{MHz}$ | 4 | 8 | 12 | Ω |
| SWITCHING PARAMETERS | | | | | | |
| $Q_g(10\text{V})$ | Total Gate Charge | $V_{GS}=10\text{V}, V_{DS}=15\text{V}, I_D=3.8\text{A}$ | | 8 | 16 | nC |
| $Q_g(4.5\text{V})$ | Total Gate Charge | | | 4 | 8 | nC |
| Q_{gs} | Gate Source Charge | | | 1 | | nC |
| Q_{gd} | Gate Drain Charge | | | 1.2 | | nC |
| $t_{D(on)}$ | Turn-On Delay Time | $V_{GS}=10\text{V}, V_{DS}=15\text{V}, R_L=3.95\Omega, R_{GEN}=3\Omega$ | | 2.5 | | ns |
| t_r | Turn-On Rise Time | | | 3 | | ns |
| $t_{D(off)}$ | Turn-Off Delay Time | | | 30 | | ns |
| t_f | Turn-Off Fall Time | | | 5 | | ns |
| t_{rr} | Body Diode Reverse Recovery Time | $I_F=3.8\text{A}, di/dt=500\text{A}/\mu\text{s}$ | | 5.5 | | ns |
| Q_{rr} | Body Diode Reverse Recovery Charge | $I_F=3.8\text{A}, di/dt=500\text{A}/\mu\text{s}$ | | 4 | | nC |

A. The value of R_{JJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^\circ\text{ C}$. The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=150^\circ\text{ C}$, using $\leq 10\text{s}$ junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{ C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^\circ\text{ C}$.

D. The R_{JJA} is the sum of the thermal impedance from junction to lead R_{JUL} and lead to ambient.

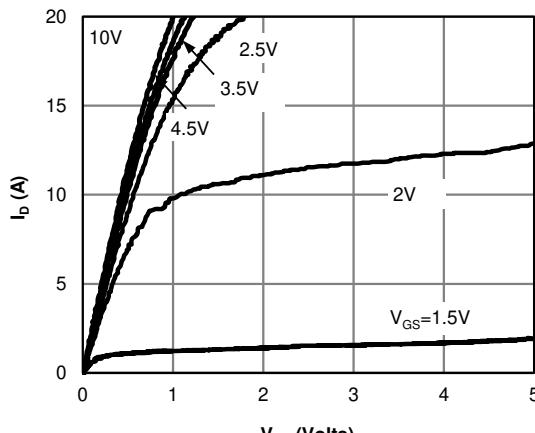
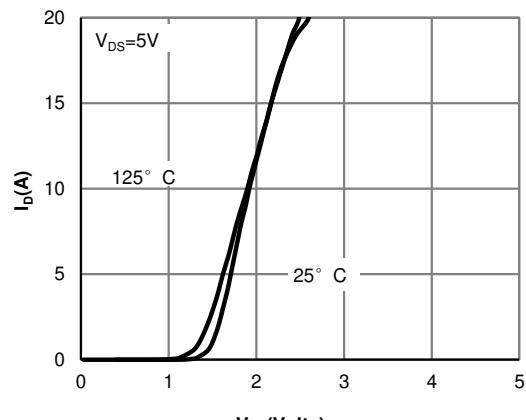
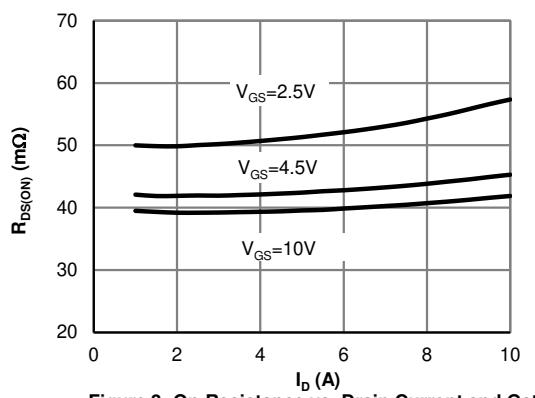
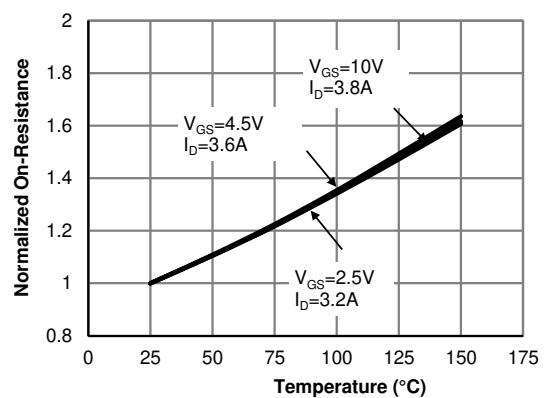
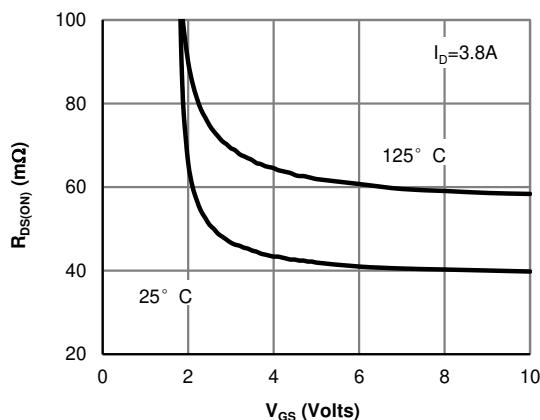
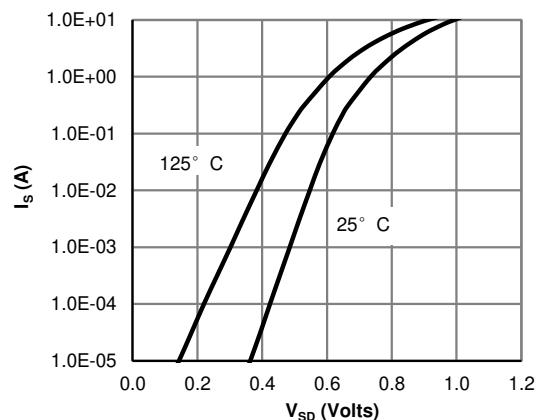
E. The static characteristics in Figures 1 to 6 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.

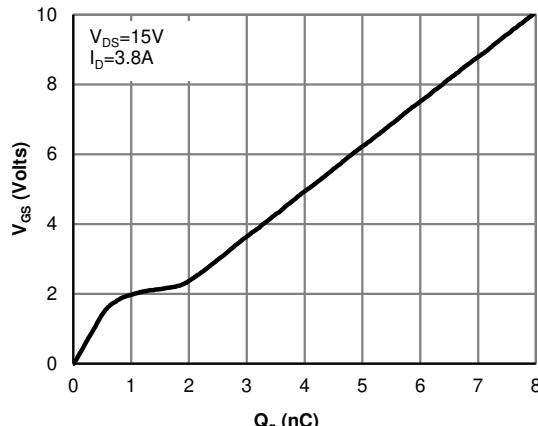
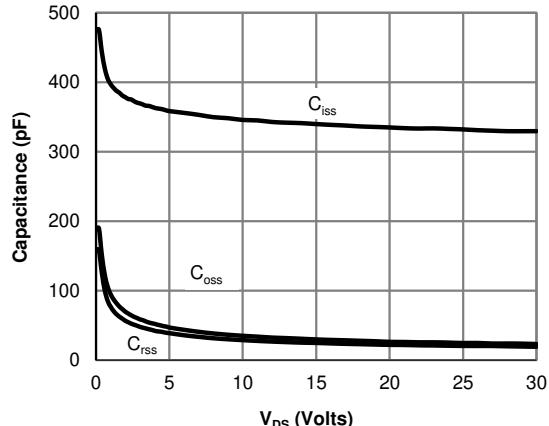
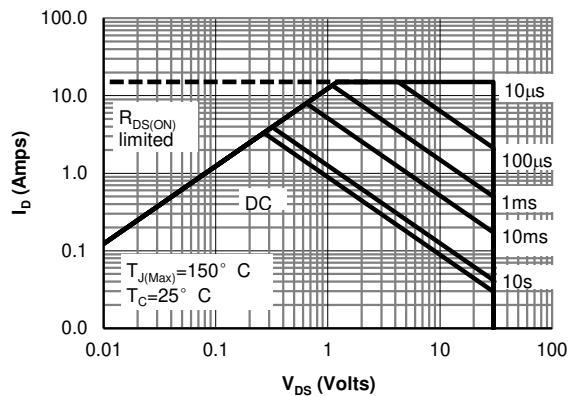
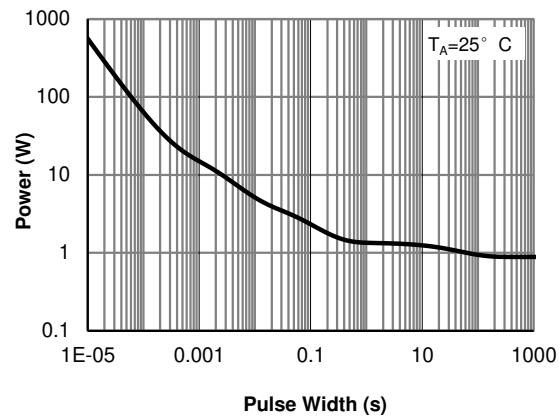
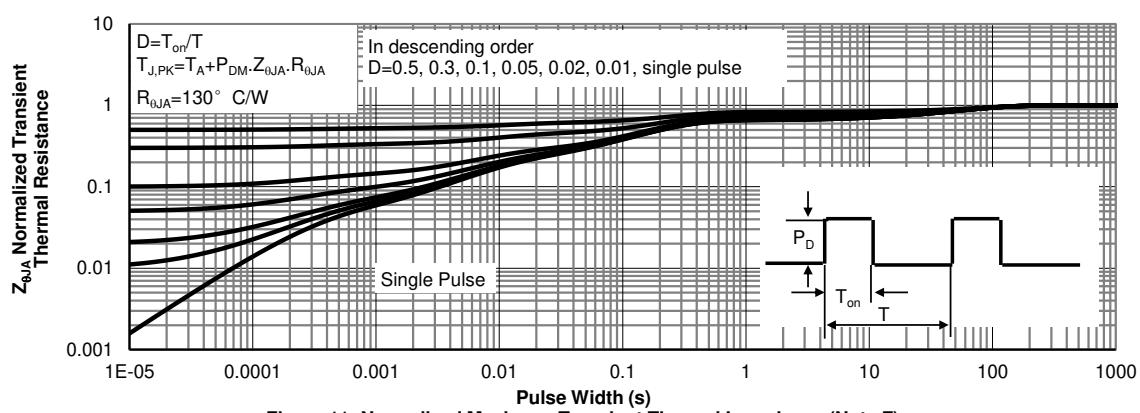
F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, assuming a maximum junction temperature of $T_{J(\text{MAX})}=150^\circ\text{ C}$. The SOA curve provides a single pulse rating.

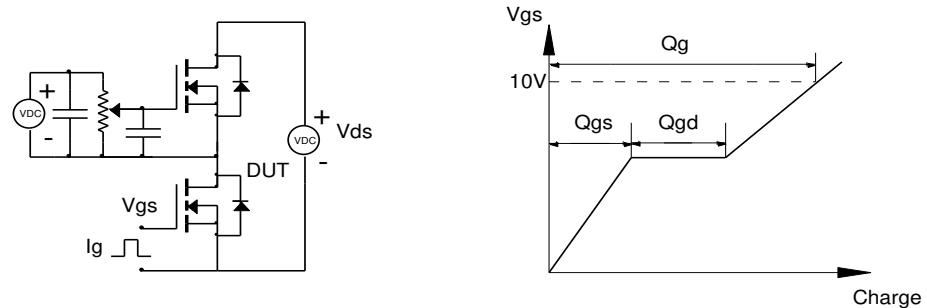
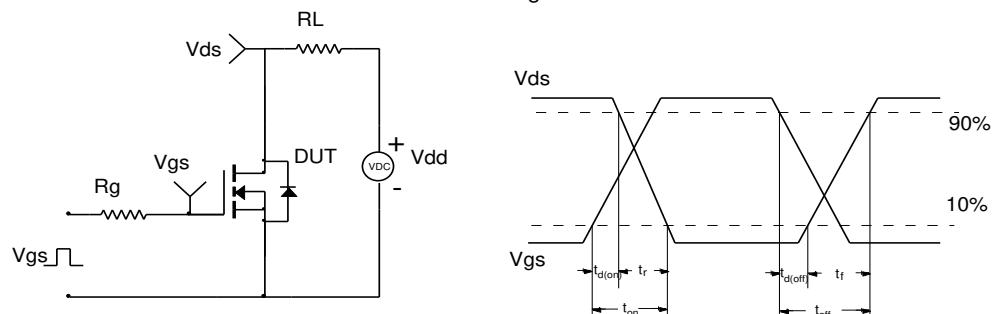
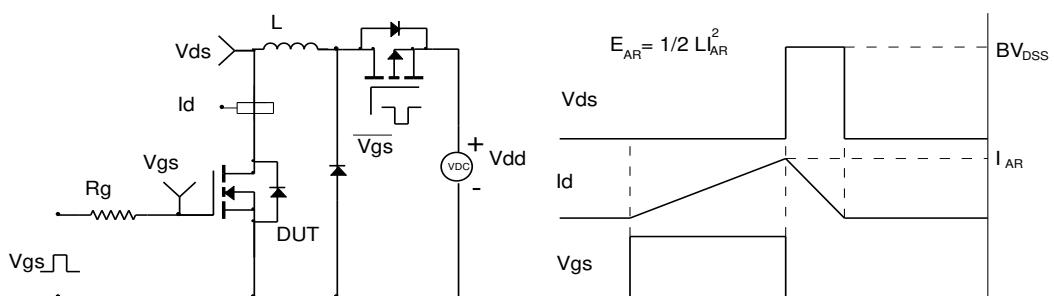
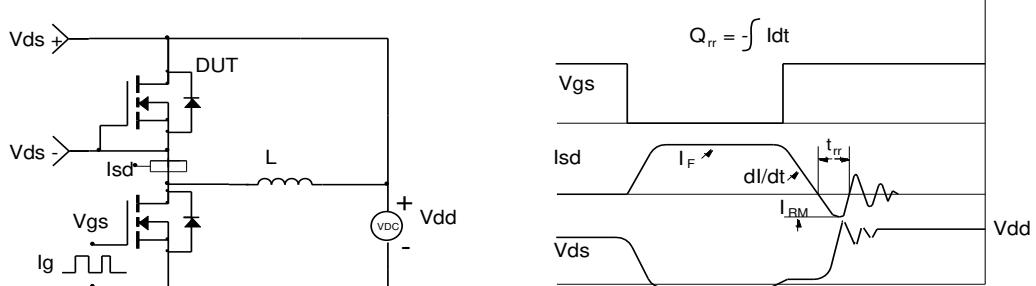
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N-Channel: TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 1: On-Region Characteristics (Note E)

Figure 2: Transfer Characteristics (Note E)

Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

Figure 4: On-Resistance vs. Junction Temperature (Note E)

Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

Figure 6: Body-Diode Characteristics (Note E)

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Figure 7: Gate-Charge Characteristics

Figure 8: Capacitance Characteristics

Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)

Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

Gate Charge Test Circuit & Waveform

Resistive Switching Test Circuit & Waveforms

Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

Diode Recovery Test Circuit & Waveforms


P-Channel Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

| Symbol | Parameter | Conditions | Min | Typ | Max | Units |
|-----------------------------|---------------------------------------|---|-------|-------|----------|------------------|
| STATIC PARAMETERS | | | | | | |
| BV_{DSS} | Drain-Source Breakdown Voltage | $I_D=-250\mu\text{A}, V_{GS}=0\text{V}$ | -20 | | | V |
| I_{DSS} | Zero Gate Voltage Drain Current | $V_{DS}=-20\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$ | | -1 | -5 | μA |
| I_{GSS} | Gate-Body leakage current | $V_{DS}=0\text{V}, V_{GS}=\pm 8\text{V}$ | | | ± 10 | μA |
| $V_{\text{GS(th)}}$ | Gate Threshold Voltage | $V_{DS}=V_{GS}, I_D=-250\mu\text{A}$ | -0.15 | -0.55 | -0.95 | V |
| $R_{\text{DS(ON)}}$ | Static Drain-Source On-Resistance | $V_{GS}=-4.5\text{V}, I_D=-4.5\text{A}$ $T_J=125^\circ\text{C}$ | 36 | 44 | | $\text{m}\Omega$ |
| | | $V_{GS}=-2.5\text{V}, I_D=-4\text{A}$ | 46 | 59 | | $\text{m}\Omega$ |
| | | $V_{GS}=-1.8\text{V}, I_D=-3\text{A}$ | 60 | 80 | | $\text{m}\Omega$ |
| g_{FS} | Forward Transconductance | $V_{DS}=-5\text{V}, I_D=-4.5\text{A}$ | 26 | | | S |
| V_{SD} | Diode Forward Voltage | $I_S=-1\text{A}, V_{GS}=0\text{V}$ | | -0.7 | -1 | V |
| I_S | Maximum Body-Diode Continuous Current | | | | -2 | A |
| DYNAMIC PARAMETERS | | | | | | |
| C_{iss} | Input Capacitance | $V_{GS}=0\text{V}, V_{DS}=-10\text{V}, f=1\text{MHz}$ | | 930 | | pF |
| C_{oss} | Output Capacitance | | | 90 | | pF |
| C_{rss} | Reverse Transfer Capacitance | | | 80 | | pF |
| R_g | Gate resistance | $V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$ | 15 | 30 | | Ω |
| SWITCHING PARAMETERS | | | | | | |
| $Q_g(4.5\text{V})$ | Total Gate Charge | $V_{GS}=-4.5\text{V}, V_{DS}=-10\text{V}, I_D=-4.5\text{A}$ | | 8.5 | 17 | nC |
| Q_{gs} | Gate Source Charge | | | 1 | | nC |
| Q_{gd} | Gate Drain Charge | | | 2.5 | | nC |
| $t_{\text{D(on)}}$ | Turn-On Delay Time | $V_{GS}=-4.5\text{V}, V_{DS}=-10\text{V}, R_L=2.22\Omega, R_{\text{GEN}}=3\Omega$ | | 12 | | ns |
| t_r | Turn-On Rise Time | | | 11 | | ns |
| $t_{\text{D(off)}}$ | Turn-Off Delay Time | | | 82 | | ns |
| t_f | Turn-Off Fall Time | | | 35 | | ns |
| t_{rr} | Body Diode Reverse Recovery Time | $I_F=-4.5\text{A}, di/dt=500\text{A}/\mu\text{s}$ | | 25 | | ns |
| Q_{rr} | Body Diode Reverse Recovery Charge | $I_F=-4.5\text{A}, di/dt=500\text{A}/\mu\text{s}$ | | 37 | | nC |

A. The value of R_{JJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=150^\circ\text{C}$, using $\leq 10\text{s}$ junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^\circ\text{C}$.

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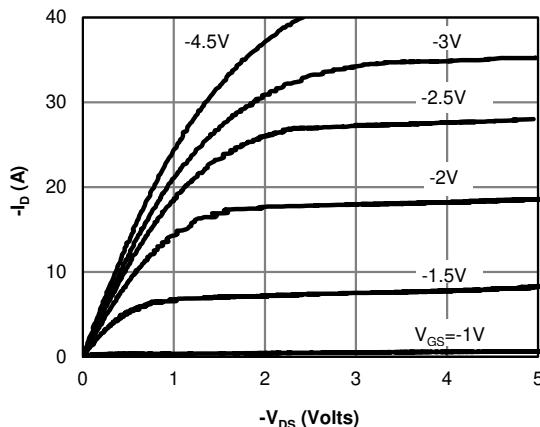
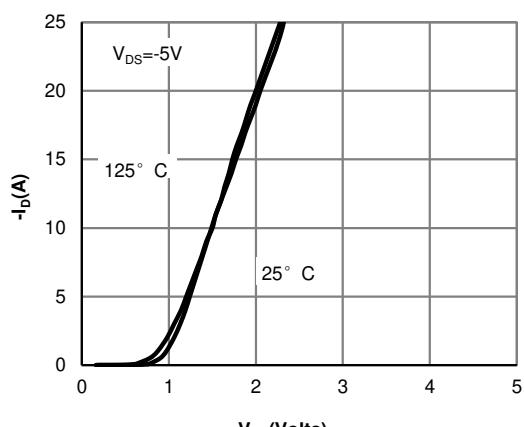
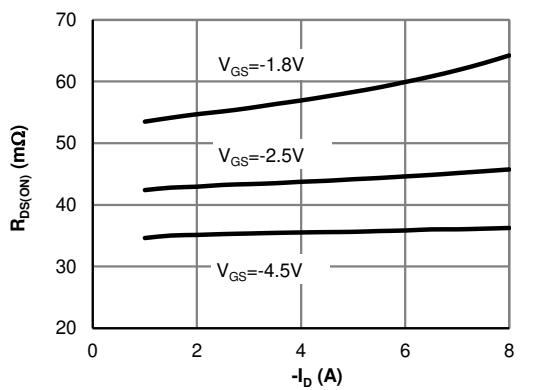
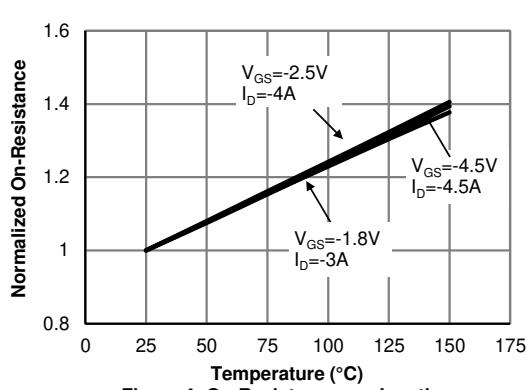
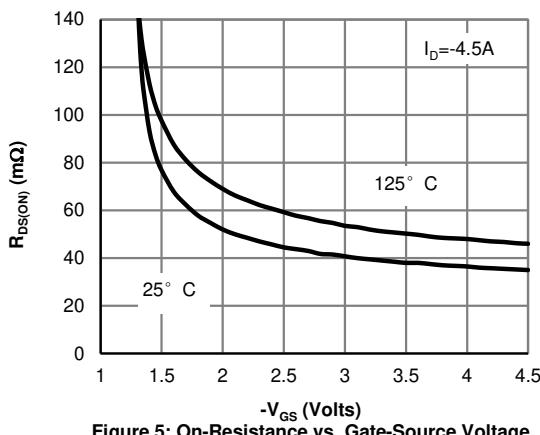
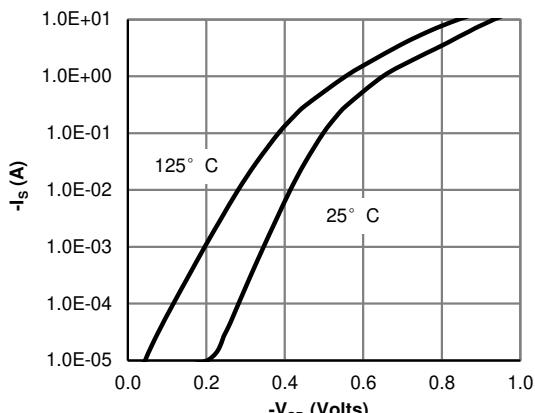
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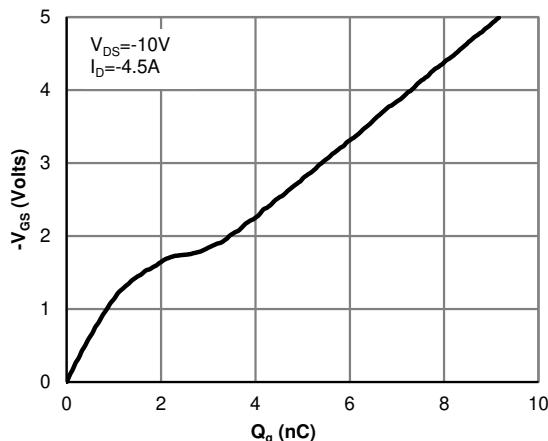
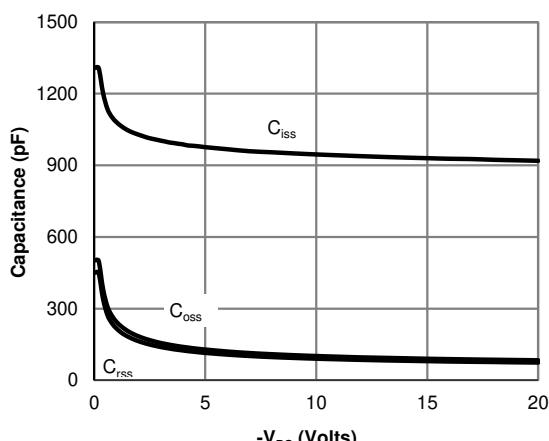
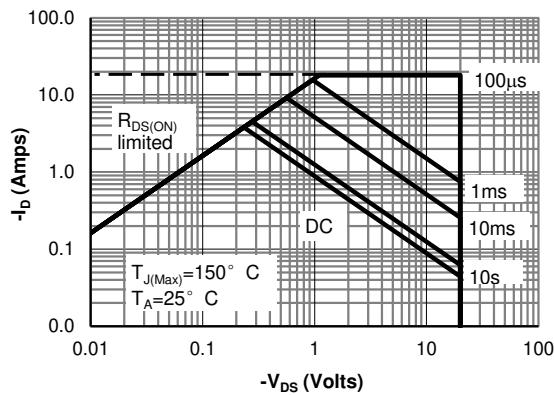
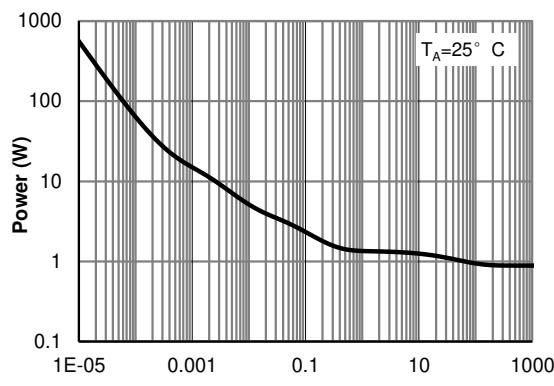
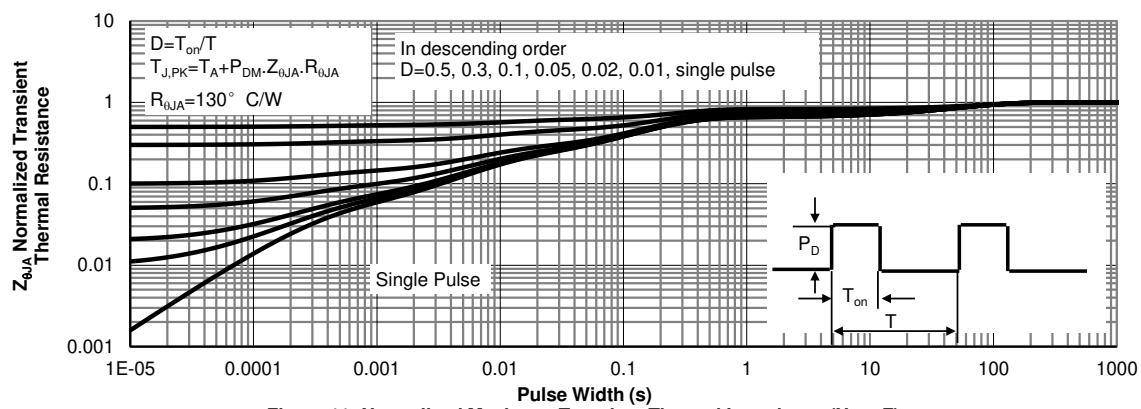
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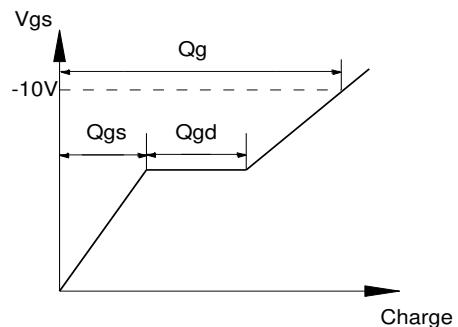
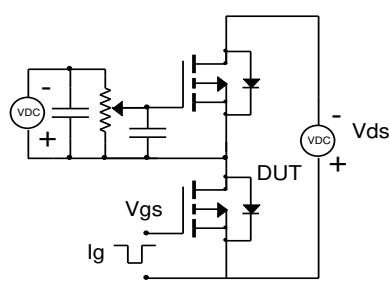
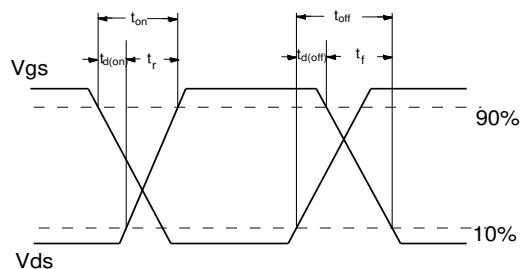
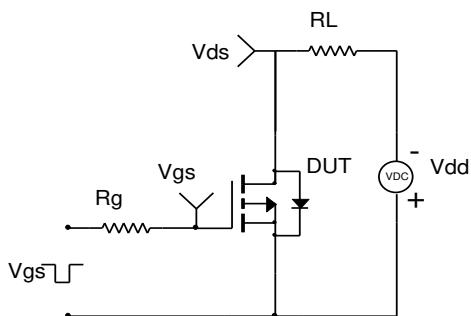
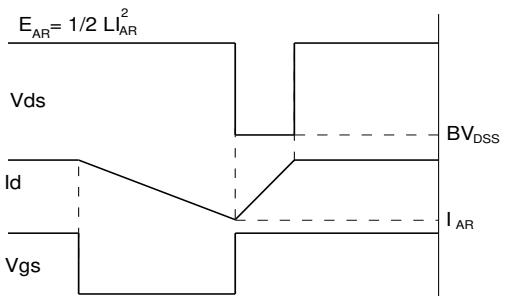
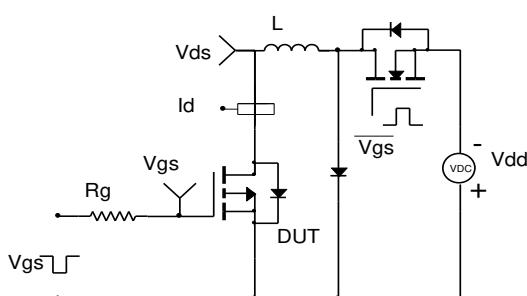
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